



UL 1699B

STANDARD FOR SAFETY

Photovoltaic (PV) DC Arc-Fault Circuit Protection

UL Standard for Safety for Photovoltaic (PV) DC Arc-Fault Circuit Protection, UL 1699B

First Edition, Dated August 22, 2018

Summary of Topics

This revision of ANSI/UL 1699B dated July 9, 2024 includes the following changes in requirements:

– Allowance of alternative test method according to an IEC standard; [38.1](#) and [38.4](#)

Text that has been changed in any manner or impacted by ULSE's electronic publishing system is marked with a vertical line in the margin.

The revised requirements are substantially in accordance with Proposal(s) on this subject dated May 31, 2024.

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UL 1699B

Standard for Photovoltaic (PV) DC Arc-Fault Circuit Protection

First Edition

August 22, 2018

This ANSI/UL Standard for Safety consists of the First Edition including revisions through July 9, 2024.

The most recent designation of ANSI/UL 1699B as an American National Standard (ANSI) occurred on July 9, 2024. ANSI approval for a standard does not include the Cover Page, Transmittal Pages, and Title Page.

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PART 1 – ALL DEVICES

INTRODUCTION

1 Scope

1.1 These requirements cover DC photovoltaic arc-fault circuit protection devices intended for use in solar photovoltaic electrical energy systems as described in Article 690 of the National Electrical Code, NFPA 70. This protection is intended to mitigate the effects of arcing faults that may pose a risk of fire ignition under certain conditions if the arcing persists.

1.2 These requirements cover devices including photovoltaic (PV) dc arc-fault circuit-interrupters (AFCI), arc-fault detectors (AFD), interrupting devices (ID) and inverters, converters, and charge controllers with integral arc-fault circuit-interrupter protection.

1.3 These requirements cover devices rated 1500 volts or less. They are intended for use in dc electrical systems that are supplied by a photovoltaic source, such as a module with solar cells designed to generate dc power when exposed to sunlight.

1.4 These devices are not intended to detect glowing connections.

1.5 In Part 1 of these requirements the term "device" is used generically to apply to all of the devices covered by these requirements and is modified when the requirement does not apply to all types. In Part 2 and Part 3 of these requirements the term "device" is used generically to apply to all devices covered by the particular part of this Standard, and is modified when the requirement does not apply to all types.

1.6 A device that is also intended to perform other functions, such as overcurrent protection, disconnects, combiner boxes, inverters, or other PV system functions or any combination thereof, shall additionally comply with the requirements of the applicable Standard or Standards that cover devices that provide those functions as intended for use in PV systems.

2 Glossary

2.1 For the purposes of this standard the following definitions apply.

2.2 ANNUNCIATOR – A feature of a device that gives an indication upon the functioning of a protective device.

2.3 ARCING – A luminous discharge of electricity across an insulating medium, usually accompanied by the partial volatilization of the electrodes.

2.4 ARCING FAULT – An unintentional arcing condition in a circuit.

2.5 CELL – The basic photovoltaic device that generates electricity when exposed to sunlight.

2.6 CHARGE CONTROLLER – A device intended to control the charging process of storage batteries used in photovoltaic power systems.

2.7 CONVERTER (DC) – A device that accepts dc power input and converts it to another form of dc power.

2.8 DUT – Device under test.

2.9 FUNCTIONAL INSULATION – Insulation that is necessary only for the functioning of the equipment.

2.10 INVERTER – An electronic device that changes dc power to ac power.

2.11 INTERRUPTING CONTACT – A contact device inserted in series with the source and/or load. It is intended to stop the flow of arcing current by opening the circuit and may be a mechanical contact set with an air gap or a solid state switching device.

2.12 MICROELECTRONICS – Monolithic, hybrid, or module circuits, where the internal circuit connections are not accessible exclusive of provided external connection pins or pads. The circuits are capable of functioning in the analogue mode, digital mode, or a combination of the two modes. Examples of microelectronics include: ASICs, ROMs, RAMs, PROMs, EPROMs, PALs, and PLDs. See [2.18](#).

2.13 OPERATION INHIBITION – Denotes the concealment of an arcing fault by the normal operation of certain circuit components.

2.14 PARALLEL ARCING – Arcing that is in parallel with the load, such as between the positive and negative conductors, or between any two conductors or, any single conductor and ground.

2.15 PHOTOVOLTAIC (PV) DC ARC-FAULT CIRCUIT-INTERRUPTER (PV AFCI) – A device that is intended to be installed in a photovoltaic energy system to interrupt power delivered to an arcing fault when an arcing fault is detected by the AFCI. It is intended to provide protection to the PV system from unwanted effects of arcing.

2.16 PHOTOVOLTAIC (PV) DC ARC-FAULT DETECTOR (PV AFD) – A device that is intended to provide protection to the PV system from unwanted effects of arcing by enabling an interruption or shorting device to interrupt power delivered to an arcing fault.

2.17 PHOTOVOLTAIC (PV) DC INTERRUPTING DEVICE (PV ID) – A device that is intended for installation in a photovoltaic energy system to interrupt a detected arcing fault. The device is generally enabled by another device which detects arcing, such an arc-fault detector. The device can perform an interruption or shorting function as appropriate to interrupt power delivered to an arcing fault.

2.18 PROGRAMMABLE COMPONENT – Any microelectronic hardware that can be programmed in the design center, the factory, or in the field. Here the term "programmable" is taken to be "any manner in which one can alter the software wherein the behavior of the component can be altered." The microelectronics defined in [2.12](#) are examples of programmable components.

2.19 PV MODULE – The smallest environmentally protected assembly of solar cells and ancillary parts, such as interconnects and terminals, intended to generate dc power under sunlight.

2.20 SERIES ARCING – Arcing that is in series with the load and is the result of a failure in the intended continuity of a conductor, connection, module or other system components in the direct current PV source and output circuits.

2.21 SHUNTING CONTACT – A contact device inserted in parallel with the source and/or load. It is intended to stop the flow of arcing current by short circuiting the supply or shunting current around the arcing fault location. It may be a mechanical contact set with an air gap or a solid state switching device.

2.22 TYPE 1 DEVICE – A photovoltaic device that is intended to detect or interrupt series arcing faults.

2.23 UNWANTED TRIP – A tripping function in response to a condition that is not an arcing fault but a condition that occurs as part of the normal or anticipated operation of circuit components.

3 Components

3.1 Except as indicated in [3.2](#), a component of a product covered by this standard shall comply with the requirements for that component. See Appendix [A](#) for a list of standards covering components generally used in the products covered by this standard.

3.2 A component is not required to comply with a specific requirement that:

- a) Involves a feature or characteristic not required in the application of the component in the product covered by this standard, or
- b) Is superseded by a requirement in this standard.

3.3 A component shall be used in accordance with its rating established for the intended conditions of use.

3.4 Specific components are incomplete in construction features or restricted in performance capabilities. Such components are intended for use only under limited conditions, such as certain temperatures not exceeding specified limits, and shall be used only under those specific conditions.

4 Units of Measurement

4.1 Values stated without parentheses are the requirement. Values in parentheses are explanatory or approximate information.

5 Undated References

5.1 Any undated reference to a code or standard appearing in the requirements of this standard shall be interpreted as referring to the latest edition of that code or standard.

CONSTRUCTION

6 General

6.1 All devices shall comply with the construction requirements in Sections [7](#) – [14](#) of this standard.

7 Corrosion Protection

7.1 Parts, in addition to enclosures, shall be protected against corrosion if failure of such parts would be likely to result in a hazardous condition such as the inability of the device to perform its intended function. Compliance is determined by the Corrosion Test, Section [38](#).

8 Current Carrying Parts

8.1 Current-carrying parts shall be of silver, a silver alloy, copper, a copper alloy or other metal acceptable for the application. Screws, nuts, or wire binding screws made of iron or steel and corrosion protected, shall be permitted to be used to secure live parts, but shall not be depended upon to carry current.

9 Internal Wiring

9.1 The gauge and insulation of wires shall withstand the mechanical and electrical stresses of service. Wires smaller than 24 AWG (0.21 mm²) shall be investigated for the application.

10 Insulation

10.1 A device shall have at least functional insulation throughout. Materials shall be suitable for the temperature, voltage and conditions of service.

11 Power Supply

11.1 The power supply of a device shall be a commercial light and power source available in a building, dc power from a photovoltaic source, or both. The power supply shall be capable of allowing the device to function and provide protection at all times when the danger of an arcing fault is present.

11.2 When conducting tests in accordance with Part 2 or Part 3 of this standard, tests applicable to each intended power supply type as mentioned in [11.1](#) shall be conducted.

12 Operating Mechanism

12.1 Compliance with the provisions of arcing fault interruption shall not be prevented by manipulation or restraint of accessible levers, knobs, and the like of a device.

13 Programmable Circuit Components

13.1 If a device employs a programmable circuit component such as a microprocessor in its arc fault detection or interruption system, or in its test circuits, that portion of the device shall be investigated in accordance with the Standard for Software in Programmable Components, UL 1998, as defined in [13.2](#) – [13.9](#). As an alternative to UL 1998 and the requirements as defined in [13.2](#) – [13.9](#), the Standard for Automatic Electrical Controls – Part 1: General Requirements, UL 60730-1, Annex H, or Functional Safety of Electrical/Electronic/Programmable Electronic Safety Related Systems, IEC 61508, may be used to evaluate functional safety. IEC 61508 evaluations shall be SIL2 or higher.

13.2 All of the requirements of the Standard for Software in Programmable Components, UL 1998, apply to programmable components employed in a device as mentioned in [13.1](#), except as modified by [13.3](#) – [13.9](#).

13.3 The risks to be considered for the Risk Analysis portion of UL 1998 include the following scenarios:

- a) Unwanted tripping;
- b) Failure to trip under conditions where tripping should occur; and
- c) Failure of a test circuit to complete evaluation.

13.4 The Tool Qualification requirements from UL 1998 are modified in [13.5](#) and [13.6](#).

13.5 All tools used in the design, implementation, and verification of software shall be documented. The documentation shall include:

- a) The name of the tool supplier or developer;
- b) The model, application, or trade name of the tool;
- c) The tool version identification;
- d) A description of the purpose for which the tool is used; and
- e) A list of known errors, faults or failures of the tool performance, such as a "bug list".

13.6 Software tools are defined as software or hardware used in the development, testing, analysis, or maintenance of a program or its documentation. Examples include compilers, assemblers, timing analyzers, logic analyzers, test case generators, simulators, emulators, and similar tools.

13.7 Means shall be employed to address all microelectronic hardware failure modes identified in the Risk Analysis of [13.3](#). The analysis shall consider all possible combinations of microelectronic hardware failures, software faults, and other events that are capable of resulting in a risk. This includes, for example, microelectronic hardware failures that cause software faults that are capable of resulting in a risk. Detection of failure modes shall be at a frequency and adequacy suitable for the application.

13.8 One approach to comply with [13.7](#) is for the manufacturer to:

- a) Identify failure modes;
- b) Determine safety impact of failure modes;
- c) Design and provide means to detect the failure modes that have an impact on safety;
- d) Demonstrate that coverage provided by detection means is at a frequency and effective level suitable for the application; and
- e) Provide evidence that the failure rate of microelectronic components is suitable for the application.

13.9 The requirements in UL 1998 addressing user interfaces do not apply.

14 Electronic Interruption

14.1 General

14.1.1 Solid state components used in place of air gap contacts to interrupt or shunt an arc fault shall comply with [14.2](#) – [14.4](#) as applicable.

14.2 "Off" state or stand-by mode current

14.2.1 When arcing is interrupted by an interrupting contact using electronic means, the available current with the system in the "off" state or stand-by mode after interruption shall not exceed 250 mA with the DC system at maximum rated voltage.

14.3 Reliability

14.3.1 Except as indicated in [14.3.2](#), solid-state components that function as an interrupting contact or shunting contact to terminate an arc fault shall be investigated in accordance with the Standard for Tests for Safety-Related Controls Employing Solid-State Devices, UL 991. This UL 991 investigation shall include the failure of any components between the interrupting or shunting components and the product's input and or output wiring connections that may prevent the interrupting or shunting devices from clearing an arc fault.

14.3.2 If degradation and/or failure of these components is detected and indicated by the test circuit, then only the test circuit shall be investigated in accordance with UL 991.

14.3.3 When the Standard for Automatic Electrical Controls – Part 1: General Requirements, UL 60730-1, Annex H, or Functional Safety of Electrical/Electronic/Programmable Electronic Safety Related Systems, IEC 61508, are used as an alternative to UL 1998 in order to determine compliance with the

requirements as defined in Programmable Circuit Components, Section [13](#), these standards may be used to evaluate the hardware requirements of UL 991.

14.4 Programmable circuit components

14.4.1 If a device employs a programmable circuit component such as a microprocessor to implement the test circuit function mentioned above in [14.3.2](#), that portion of the circuit shall be investigated in accordance with Programmable Circuit Components, Section [13](#).

MANUFACTURING AND PRODUCTION LINE TESTS

15 General

15.1 Each device shall be subjected to the manufacturing and production-line tests described in Appendix [B](#).

PART 2 – PV AFCI, PV AFD, AND PV ID DEVICES

CONSTRUCTION

16 General

16.1 A PV AFCI, PV AFD, or PV ID device shall comply with the construction requirements of Part 1 of this Standard as well as Sections [17](#) – [23](#).

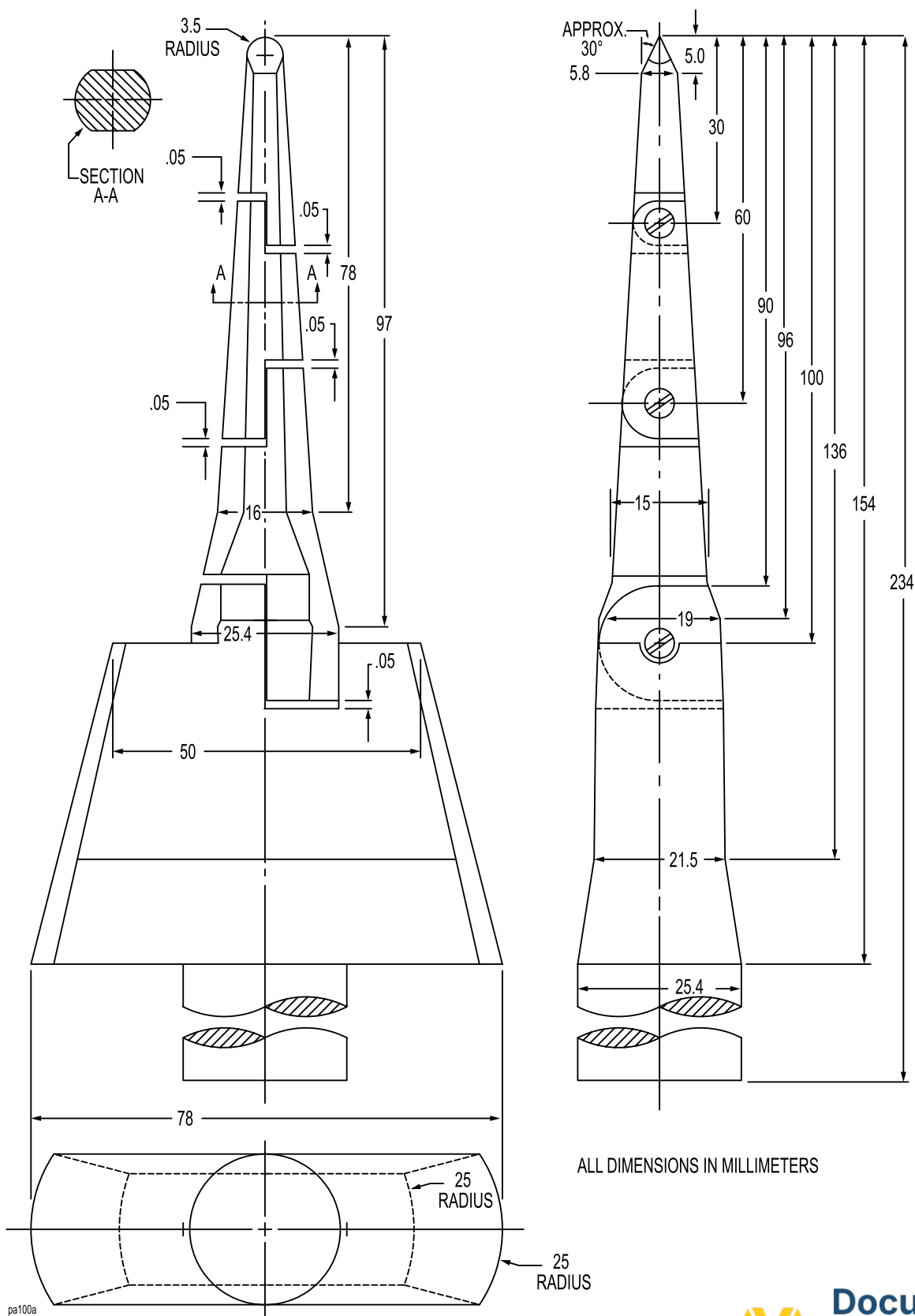
17 Accessibility of Energized Parts

17.1 Parts of a device shall not be accessible when they are installed as intended and energized.

17.2 Parts are considered to be accessible if they can be touched using the articulated probe shown in [Figure 17.1](#).

17.3 Access to the trip mechanism shall not be attainable with ordinary tools.

Figure 17.1
Articulated probe



18 Spacings

18.1 Except as indicated in [18.2](#), a device shall comply with the requirements shown in [Table 18.1](#).

Table 18.1
Spacing in mm (inches)^{a,b}

Operating potential between parts							
0 – 200 V peak		201 – 400 V peak		401 – 1000 V peak		1001 – 1500 V peak	
Through air	Over surface	Through air	Over surface	Through air	Over surface	Through air	Over surface
3.2 (1/8)	6.4 (1/4)	6.4 (1/4)	9.5 (3/8)	9.5 (3/8)	12.7 (1/2)	17.8 (0.70)	30.5 (1.20)
^a Smaller spacings may be acceptable where they are inherent in a suitable component. ^b For printed wiring boards with suitable conformal coating which have been determined to comply with the requirements for conformal coatings in the Standard for Polymeric Materials – Use in Electrical Equipment Evaluations, UL 746C, spacings may be reduced to 0.8 mm (1/32 inch), and may be reduced further if the coating is determined to be suitable and it is evaluated in accordance with UL 746C for the reduced spacing.							

18.2 At field-wiring terminals, the spacings between terminals with a potential difference between them shall be not less than 6.4 mm (1/4 inch) for devices rated 200 V and less, not less than 9.5 mm (3/8 inch) for devices rated 201 – 400 V, not less than 12.7 mm (1/2 inch) for devices rated 401 – 1000 V, and not less than 30.5 mm (1.20 inch) for devices rated over 1000V.

18.3 Except as permitted in Note a of [Table 18.1](#), if a groove or a slot in insulating material is less than 0.4 mm (1/64 inch) wide, the contour of the slot or groove is to be disregarded in measuring spacings over the surface.

18.4 Spacings measured along the boundary of insulating materials that have been joined together are considered to be spacings over surface unless it can be shown that the dielectric strength of the boundary is not less than that of any of the materials joined.

18.5 Film-coated magnet wire is considered to be uninsulated in determining spacings.

18.6 As an alternative to the requirements specified in [18.1](#) – [18.5](#), the minimum acceptable clearances (through air spacings) and creepage distances (over surface spacings) for a printed wiring board assembly may be evaluated as specified in [18.7](#) – [18.9](#) using the applicable requirements in the Standard for Insulation Coordination Including Clearances and Creepage Distances for Electrical Equipment, UL 840.

18.7 When applying the requirements in the Standard for Insulation Coordination Including Clearances and Creepage Distances for Electrical Equipment, UL 840, the environment for a printed wiring board assembly within a device is considered to be:

- a) Pollution degree 3 for an assembly without a conformal coating;
- b) Pollution degree 2 for:
 - 1) An assembly with a coating,
 - 2) An assembly without a coating when the printed wiring board is contained in a sealed housing that complies with the Dust Test, Section [45](#), or
- c) Pollution degree 1 for an assembly with a conformal coating complying with the Printed Wiring Board Coating Performance Test, in UL 840.

18.8 For Clearance B (controlled overvoltage) requirements in the Standard for Insulation Coordination Including Clearances and Creepage Distances for Electrical Equipment, UL 840, the applicable overvoltage category for line-voltage circuits is Category III for PV AFCIs, PV AFDs, and PV IDs. Category I is applicable to low-voltage circuits if short circuit between the parts involved may result in an increase in the risk of fire or electric shock. Any overvoltage protection device needed to achieve these categories shall be provided as an integral part of the device.

18.9 Where measurement of clearances and creepage distances is involved to establish the minimum spacings, the methods specified in Measurement of Clearance and Creepage Distances in the Standard for Insulation Coordination Including Clearances and Creepage Distances for Electrical Equipment, UL 840, shall be used.

18.10 As an alternative to the requirements specified in this Section, Creepage and Clearance requirements may be evaluated in accordance with Tables 13 and 14 of the Standard for Power Converters for use in Photovoltaic Power Systems – Part 1: General Requirements, UL 62109-1.

19 Terminals

19.1 General

19.1.1 A device shall have terminals suitable for the application. Terminals that are intended to be wired in the field shall be in the form of terminal leads, wire binding screws or pressure-wire terminals. The terminals shall comply with [19.2](#), [19.3](#), or [19.4](#) as applicable.

19.1.2 A device may also be evaluated for use with PV wire, or other class and strand configurations as indicated by marking. See [47.9](#).

19.2 Terminal leads

19.2.1 Terminal leads shall differ by no more than two wire sizes from the size that would have an ampacity in accordance with the National Electrical Code (NEC), ANSI/NFPA 70 for the rating of the device.

19.2.2 The insulation of lead type terminals shall be rated for the application and be of a color that conforms with the requirements of the NEC, that is white or gray for the grounded conductor and green or green with a yellow stripe for the grounding conductor.

19.2.3 The free length of a terminal lead shall be at least 152 mm (6 inches).

19.2.4 A terminal lead shall be constructed so as to withstand the stress of normal handling without damage to itself or the device. See Mechanical Tests, Section [44](#).

19.3 Wire binding screw terminals

19.3.1 A wire binding screw shall be permitted to be used at a field wiring terminal intended for the connection of a 10 AWG (5.3 mm²) or smaller wire if upturned lugs or the equivalent are provided to retain the wire under the head of the screw even though the screw becomes loosened.

19.3.2 A screw and washer construction used at a field wiring terminal shall not be smaller than No. 10 (4.8 mm) with no more than 32 threads per inch (25.4 mm). A minimum of two threads shall be engaged.

19.3.3 A terminal plate tapped for a wire binding screw shall be of metal not less than 1.27 mm (0.05 inch) thick and shall have not less than 2 full threads in the metal; except that a plate made of a special

alloy not less than 0.76 mm (0.03 inch) thick shall be permitted if the tapped threads have the necessary mechanical strength.

19.3.4 A terminal plate shall be permitted to have the metal extruded at the tapped hole so as to give the thickness necessary for at least 2 full threads provided that the thickness for the unextruded metal is not less than the pitch of the thread.

19.4 Pressure wire terminals

19.4.1 Pressure wire terminals provided with a device shall comply with the Standard for Wire Connectors, UL 486A-486B or the Standard for Equipment Wiring Terminals for Use with Aluminum and/or Copper Conductors, UL 486E.

19.4.2 The tightening torque for a field wiring terminal shall be in accordance with the Standard for Wire Connectors, UL 486A-486B, the Standard for Equipment Wiring Terminals for Use with Aluminum and/or Copper Conductors, UL 486E, or as specified by the device manufacturer and the device shall be marked as required by 50.10. The specified tightening torque shall not be less than 90 percent and not more than 100 percent of the value used in the static heating test as specified in UL 486A-486B or UL 486E, for the wire size corresponding to the ampere rating of the device. See Mechanical Tests, Section [44](#). Torque values shall be permitted to be less than 90 percent if the connector is investigated in accordance with the lesser assigned torque value.

19.4.3 A pressure wire connector shall be prevented from moving (rotating) so as to strain connections or reduce spacings to unacceptable values.

20 Enclosure

20.1 When a device is provided with its own enclosure, the enclosure shall comply with the requirements in the Standard for Enclosures for Electrical Equipment, Non-Environmental Considerations, UL 50, and the applicable enclosure requirements for the intended environment in the Standard for Enclosures for Electrical Equipment, Environmental Considerations, UL 50E.

21 Grounding

21.1 All accessible parts of a PV AFCI, AFD or ID device that are likely to become energized if there should be arc-over, insulation failure or the like, shall be connected together and to the terminal intended for the equipment grounding conductor.

21.2 A device intended to be connected to multiple power sources, such as a PV power source and a commercial light and power source, shall incorporate terminals or provisions for connecting the equipment grounding conductor from each source.

22 Annunciator

22.1 A PV AFCI or AFD device exceeding the limits of region A as defined in [Figure 29.9](#) shall be provided with an annunciator (local or remote) that provides a visual indication that the device has operated when an arc fault is detected. This indication shall not reset automatically after exceeding the limits defined in [29.1.8](#).

22.2 It shall be permissible for the indication to be manually reset by remote means.

23 Test Circuits or Methods

23.1 A PV AFCI or AFD device shall be provided with a manual or automatic test circuit or method complying with [23.2](#) – [23.7](#).

23.2 The arc detection circuit or software shall be tested by simulating an arc or by other means that offer equivalent levels of protection. Equivalent methods or means shall be agreed upon by all concerned parties and documented in the test results. The manual test circuit or method shall allow for periodic testing of the device by manual means that does not require the use of a tool.

23.3 Operation of the manual test circuit shall cause the contacts of the PV AFCI device to open or a PV AFD device to activate its output such that an associated PV ID or other interruption device would open. The results of the test shall be made known to the user by a positive visual indication.

23.4 Failure of a manual or automatic test shall cause the inverter, converter, or charge controller to turn off or go to a stand-by state. The results of the test shall be made known to the user by a positive visual indication. This visual indication is not required when the PV power source is inactive, but must be present when PV power is sufficient to activate the inverter or charge controller in an "off" or stand-by state.

23.5 A device may be provided with a means to actuate the test remotely. If such a feature is provided, then the device shall include a remote visual indication of the results of the test and shall also provide means for remote manual reset.

23.6 An automatic self-test feature shall test the device each time prior to supplying current from the PVDC circuit.

23.7 Any test circuit or method that employs a programmable circuit component shall comply with Section [13](#), Programmable Circuit Components.

PERFORMANCE

24 General

24.1 A PV AFCI, AFD or ID device shall comply with the applicable performance requirements in Sections [25](#) – [45](#), as detailed in [Table 24.1](#).

Table 24.1
Test sequence

Test name	Section	Conditioning / environmental ^a	Overload / endurance ^b	Other ^c
Humidity	25	X		
Leakage ^d	26	X		
Voltage surge ^e	27	X		
Environmental sequence	28	X		
Arc fault detection	29	X		
Unwanted tripping	30			X
Normal Temperature	31			X
Overvoltage ^d	32		X	

Table 24.1 Continued on Next Page

Table 24.1 Continued

Test name	Section	Conditioning / environmental ^a	Overload / endurance ^b	Other ^c
Overload	33		X	
Endurance	34		X	
Dielectric voltage withstand	35	X	X	
Abnormal Operations	36			X
Short circuit	37			X
Corrosion	38			X
Surge current ^d	39			X
Abnormal overvoltage ^d	40			X
Supplemental voltage surge ^d	41			X
Resistance to environmental noise	42			X
Electrostatic discharge	42.2			X
Radiated EMI	42.3			X
Fast transients ^d	42.4			X
Voltage surge immunity ^d	42.5			X
Conducted EMI ^e	42.6			X
Voltage dips ^d	42.7			X
Strain relief	43			X
Mechanical	44			X
Dust	45			X
^a The same representative device shall be subject to the tests in the sequence shown. ^b A new representative device shall be subject to all of the tests in the sequence shown. ^c These tests need not be conducted in the sequence shown and may be conducted on new representative devices, except when the dielectric voltage withstand is required as part of another test. ^d Only applicable to devices with built-in power supplies deriving their power from a commercial light or power source (devices with AC input). ^e Conducted at the DC input of all devices plus the AC input of devices with built-in power supplies deriving their power from a commercial light or power source (devices with AC input).				

24.2 An interrupting device, such as a PV ID, intended for use with a specific detection device, such as a PV AFD, shall be tested in combination with that device as intended.

24.3 When conducting tests in accordance with this Part, tests applicable to each intended power supply type as mentioned in [11.1](#) shall be conducted.

24.4 For tests requiring a source of PV power, the source shall consist of an array of PV modules connected in a series or series/parallel, or a simulated PV DC power source (or Solar Array/PV Simulator) having characteristics similar to a PV array. Since a simulated PV DC power source may produce unwanted tripping, or may inhibit the PV AFCI from detecting arcing, when deemed necessary, referee tests shall be made using a suitable array of PV modules. When using an actual PV array or Solar Array/PV simulator, the following optional changes can be made according to the values in [Table 29.3](#) and [Table 30.1](#):

a) The impedance of the actual interconnection conductors shall be verified and the values for the Line Impedance model (L4, L5, R3, R4) may be altered to adjust for the measured conductor values. The total impedance shall not exceed the values specified in [Table 29.3](#) and [Table 30.1](#).

b) The DC source resistance (R1, R2) of the decoupling network may be removed.

24.5 Where tests are specified to be conducted at maximum power, the PV power source shall be adjusted for its Maximum Power Point (MPP) as follows:

- a) The open circuit voltage of the PV supply shall be within 10 percent of the rated voltage of the device being tested but less than the rating of the device, and
- b) The total current capability of the PV supplies shall be at least 125 percent of the maximum DC source short circuit current rating of the DUT.

Note: If actual PV modules are used, it may be necessary to parallel two or more strings.

- c) Power may be limited by the DC source or the inverter.

25 Humidity Conditioning

25.1 A representative device is to be exposed for 168 hours to air at a relative humidity of 93 ± 2 percent at a temperature of $32.0 \pm 2.0^{\circ}\text{C}$ ($89.6 \pm 3.6^{\circ}\text{F}$). The device is to be exposed to ambient air at a temperature of at least 30°C (86°F) until thermal equilibrium is attained before being placed in the test chamber.

25.2 Following the conditioning, while still in the chamber or within 60 s after removal from the chamber, the representative device shall be connected to an appropriate source of power. Operation of the representative device shall be verified by actuating the test circuit or method.

26 Leakage Current Measurement

26.1 The leakage current of a device with a built-in power supply deriving its power from a commercial light or power source (device with an AC input), shall not be more than 0.5 mA when tested in accordance with [26.2](#) – [26.6](#).

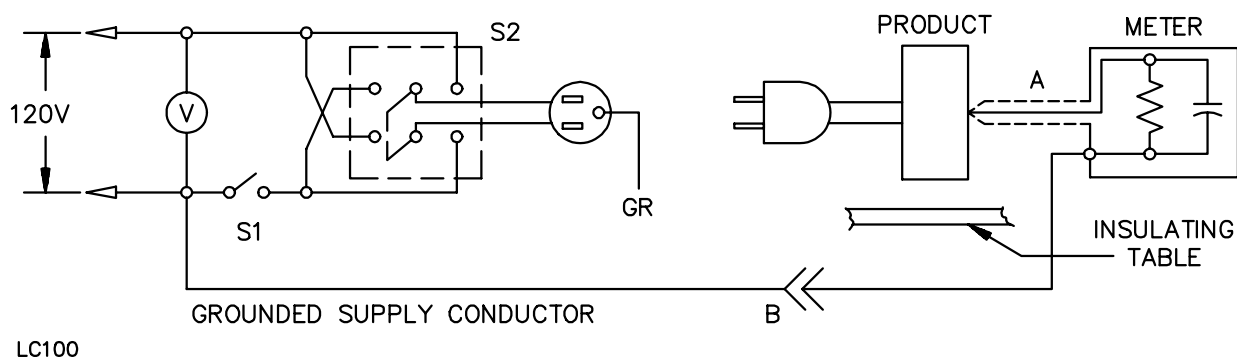
26.2 All accessible parts of a device are to be tested for leakage currents. The accessible parts are to be tested individually, collectively, and from one part to another.

26.3 If a surface other than metal is used for the enclosure or part of the enclosure, the leakage current is to be measured using metal foil with an area of 10 by 20 cm in contact with the surface. Where the surface is less than 10 by 20 cm, the metal foil is to be the same size as the surface. The metal foil is not to be pressed into openings and is not to remain in place long enough to affect the temperature of the device.

26.4 The measurement circuit for leakage current of a cord connected device is to be as shown in [Figure 26.1](#) and [Figure 26.2](#). The measurement instrument is defined in (a) – (d) below. The meter that is actually used for a measurement need only indicate the same numerical value for a measurement as would the defined instrument. The meter used need not have all the attributes of the defined instrument.

- a) The meter is to have an input impedance of 1500 ohms resistive shunted by a capacitance of 0.15 μF .
- b) The meter is to indicate 1.11 times the average of the full-wave rectified composite waveform of voltage across the resistance or current through the resistance.
- c) Over a frequency range of 0 – 100 kHz, the measurement circuitry is to have a frequency response (ratio of indicated to actual value of current) that is equal to the ratio of the impedance of a 1500-ohm resistance, shunted by a 0.15- μF capacitance, to 1500 ohms. At an indication of 0.5 mA, the measurement is to have an error of not more than five percent at any frequency within the range of 0 – 100 kHz.
- d) Unless the meter is being used to measure leakage from one part of the sample to another, the meter is to be connected between the accessible parts and the grounded supply conductor.

Figure 26.1
Leakage-current measurement circuit



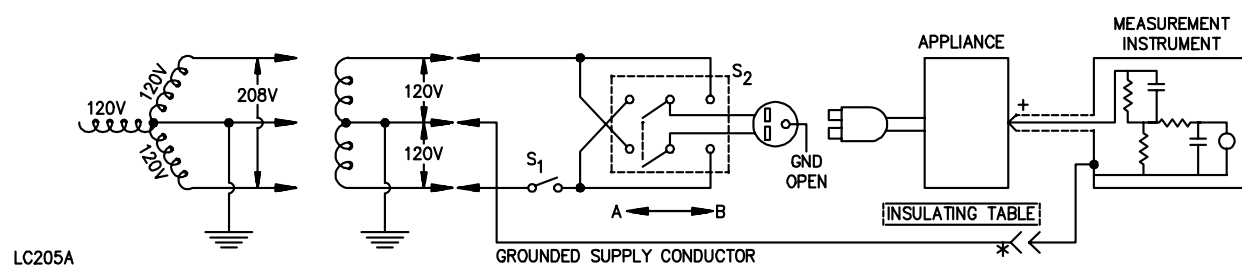
NOTES:

A – Probe with shielded lead.

B – Separated and used as clip when measuring currents from one part of the device to another.

Figure 26.2

Leakage current measurement circuit used for grounded or ungrounded 208 Vrms or 240 Vrms devices intended for connection to 3-wire neutral grounded circuits



NOTES:

1) * Separated and used as clip when measuring currents from one part of the device to another.

2) + Probe with shielded lead.

3) All voltages shown in [Figure 26.2](#) are nominal.

4) When it is not feasible to isolate the device from ground, the supply circuit shall be isolated from ground. It is possible that it will also be necessary to reverse the leads of the measurement instrument.

26.5 An AFCI that is deriving its power from the utility is to be connected to the supply by way of the terminals of the device, and tested in the same manner as a cord connected device except that switches S1 and S2 are not to be employed.

26.6 A representative device is to be tested for leakage current after the conditioning described in Humidity Conditioning, Section [25](#). If removed from the humidity chamber, the testing is to start within one minute after its removal. The grounding conductor of a cord connected device is to be open at the supply receptacle and the grounding conductor of a permanently connected device unit is not to be used. The supply voltage is to be adjusted to 110 percent of the rated voltage. The test sequence, with reference to the measuring circuit in [Figure 26.1](#), is as follows:

- a) With switch S1 open, the device is to be connected to the measurement circuit. The leakage current is to be measured using both positions of switch S2 and with the sample switching devices in all their positions.
- b) Switch S1 is then to be closed, energizing the device, and within a period of five seconds, the leakage current is to be measured using both positions of switch S2 and with the control settings varied throughout the operating range.
- c) Leakage current is to be monitored at intervals necessary to determine the maximum leakage current, with additional measurements being taken until such time as thermal equilibrium is attained. Both positions of switch S2 are to be used in determining this measurement.

27 Voltage Surge Test

27.1 General

27.1.1 Devices deriving their power from a commercial light or power source shall be subjected to the tests described in [27.2](#) and [27.3](#). The surges shall be applied to the AC input of the device.

27.1.2 In addition to the tests of [27.1.1](#), devices deriving their power from a commercial light or power source shall also be subjected to the tests described in [27.2](#) and [27.3](#) with the surges applied to the PV DC input of the device.

27.1.3 Devices deriving their power from a photovoltaic DC source shall be subjected to the tests described in [27.2](#) and [27.3](#) with the surges applied to the PV DC input of the device.

27.1.4 When applying the surges to the PV DC input of a device, the following shall apply:

- a) Surges shall be applied to the PV DC input of the device with no PV DC power applied.
- b) If the device employs a contactor or other air gap device in its DC supply circuitry, it shall be placed in the "on" position or bypassed prior to the application of the surges.

27.2 Unwanted tripping test (Ring wave)

27.2.1 A representative device shall not trip when subjected to the surges described in [27.2.2](#) – [27.2.5](#).

Note: For devices deriving their power from a photovoltaic DC source, this is a pre-conditioning test only.

27.2.2 All devices shall still be functional following the application of the ring wave surges. Functionality of a device shall be verified by connecting it to an appropriate power source and actuating the test circuit or method.